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**CITATION FORM FOR  
PATENT APPLICATION**

Applicant(s): ROSENFELDT

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(Substitute)

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Group:

**U.S. PATENTS**

Initials	Patent Number	Issue Date	Name	Class	Sub-class	Filing date

**U.S. PATENT PUBLICATIONS**

Initials	Publication No.	Pub. Date	Name	Class	Sub-class	Filing Date

**FOREIGN PATENT DOCUMENTS**

Initials	Document Number	Date	Country	Name	Translation? Yes/No/n/a
/SAT/	EP 1 113 250 B1	2/5/03	Europe	Agilent Technologies, Inc.	N/A
/SAT/	EP 1 014 033 A2	6/28/00	Europe	Anritsu Corporation	N/A
/SAT/	EP 1 202 038 A1	5/2/02	Europe	Agilent Technologies, Inc.	N/A
/SAT/	JP2000097856	4/7/00	Japan	Nippon Telegr & Teleph Corp.	YES

**OTHER DOCUMENTS (Title, Author, Date, Pages, Etc., if known)**

/SAT/	K. Takada, K. Okamoto: "Frequency-domain measurement of phase error distribution in narrow-channel arrayed-waveguide grating", Electronics Letters, Vol. 36, No. 2, January 20, 2000 pp. 160-161

Examiner's Signature: /Samuel A. Turner/

Date Considered: 08/27/2007

Initial if reference was considered, whether or not citation is in conformance with MPEP. Mark through citation if not considered.  
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